

BACK-END

TRANSISTOR

MOS-FET

IGBT

DIODE

SEMICONDUCTOR TEST SYSTEM 半導体テストシステム

CHTH1010ZZ 10000V
1000A

- This tester is an automatic test system, designed to measure the DC characteristics of transistors, MOS-FETs, IGBTs and diodes with high voltage (9.99kV/2mA) and high current (999A) at high accuracy and high speed.
- 本テスターは、トランジスタ、MOS-FET、IGBT、ダイオードのDC特性を高電圧（9.99kV/2mA）、大電流（999A）を用いて、高速且つ高精度で測定する自動測定器です。



NEW

MODEL

CHTH1010ZZ

SOFTWARE

TEST PLAN/SORT PLAN

1000/1000

BIN OUT

24

DC TEST

MEASURABLE DEVICES

NPN, N MOS-FET, N-IGBT, N-DIODE

VOLTAGE

10000V

CURRENT

1000A

TEST ITEMS (High voltage/High current)

TRANSISTOR

HICE, HICB, HBVCE, HBVCB, HIB, HHFE, HVCESAT, HVBESAT, HVFEC, HBTON

MOS-FET

HIDS, HBVDS, HBVDG, HVFSDS, HVFSDX, HVP, HVTH, HVGS(th), HVDSO, HRdSON, HIdON, HGMP

IGBT

HICE, HICES, HBVCE, HVFEC, HVFECX, HVTH, HVGE(th), HVCEON, HICON, HGMP

DIODE

HIR, HVR, HVF

DIMENSIONS & WEIGHT

MAIN UNIT

550(W)×860+485(D)×1700(H)---298kg